

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 128977		APPLICATION NO. 10/588,297	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT(S) Naoyuki KOBAYASHI et al.			
				FILING DATE August 2, 2006		GROUP 2851	
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EXAMINER					DATE CONSIDERED		
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Date: February 2, 2010

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	40	International Search Report mailed July 18, 2006 for U.S. National Phase Application No. PCT/JP2006/308040.					
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